

ACCELERATED TEST METHOD AND SYSTEM

Inventor: Yen-Fu LIU

Docket No. 4006-276

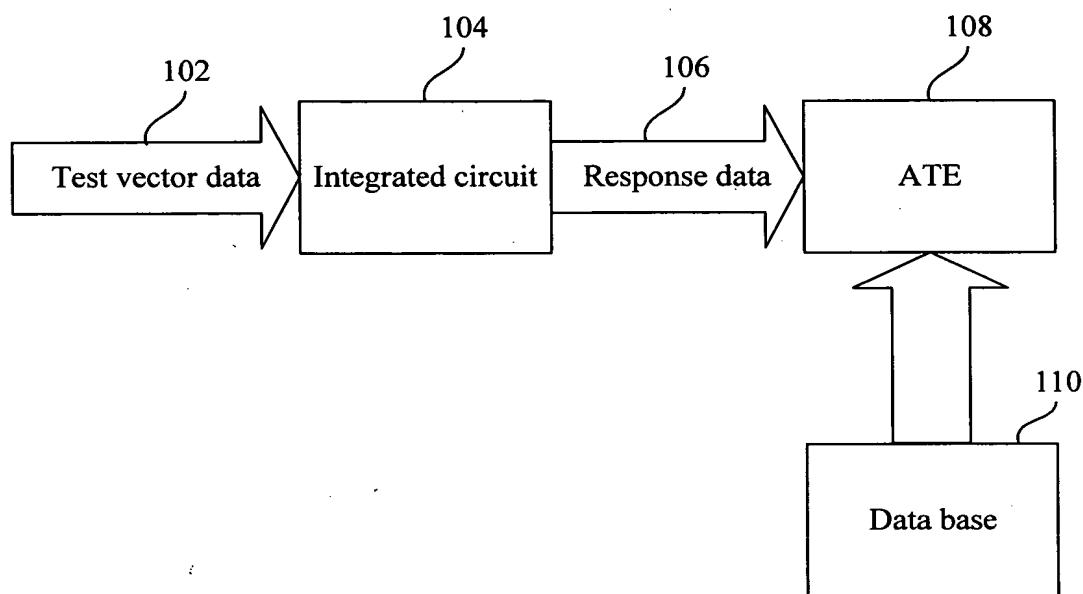


Fig. 1

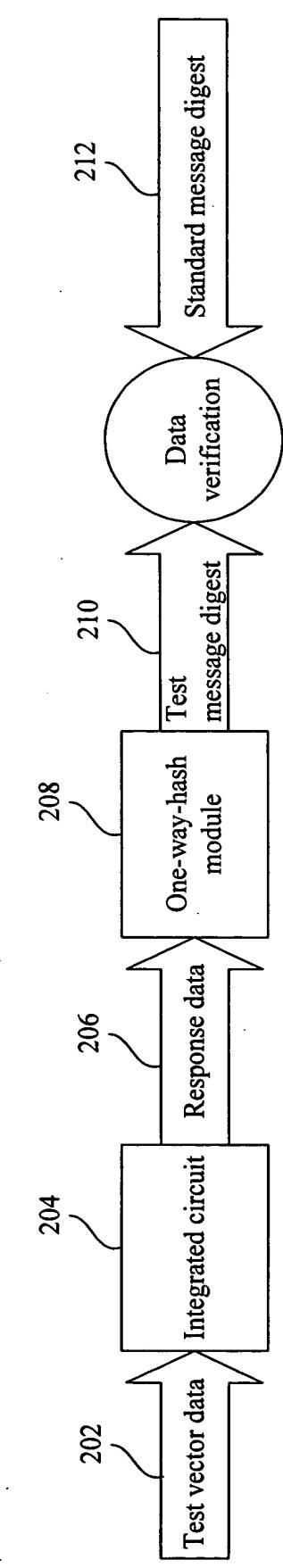


Fig. 2A

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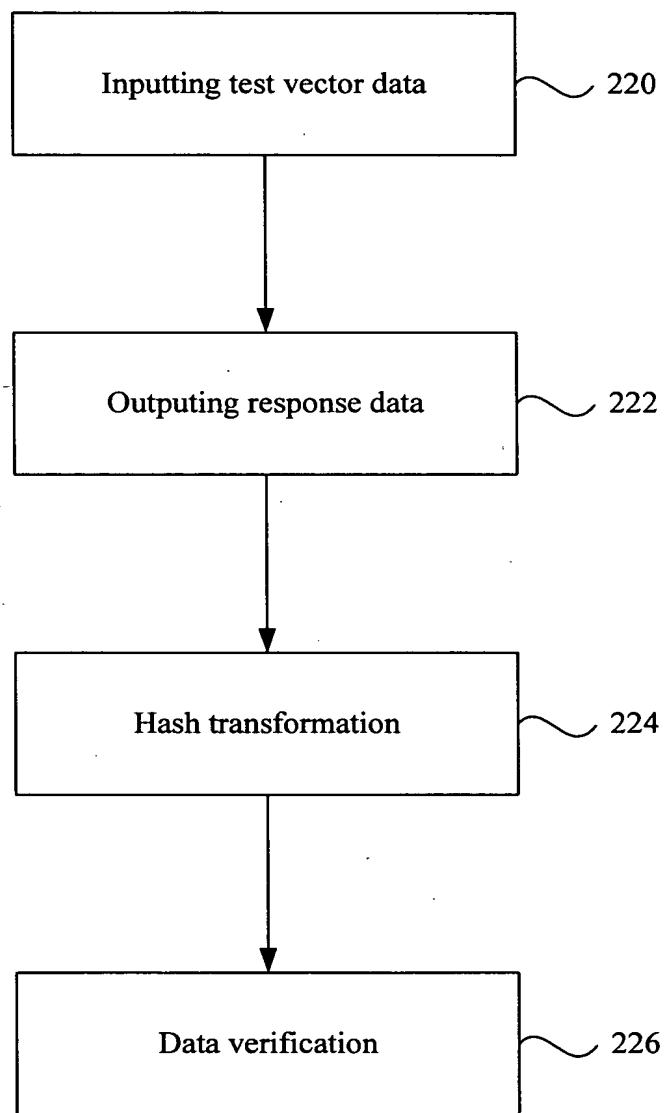


Fig. 2B

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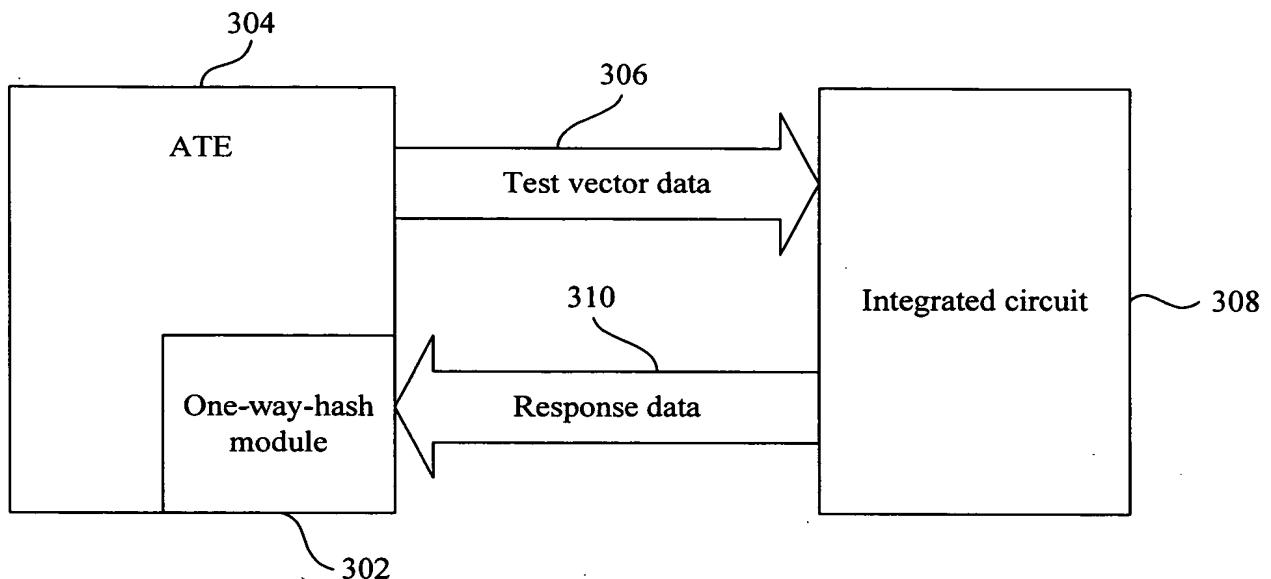


Fig. 3

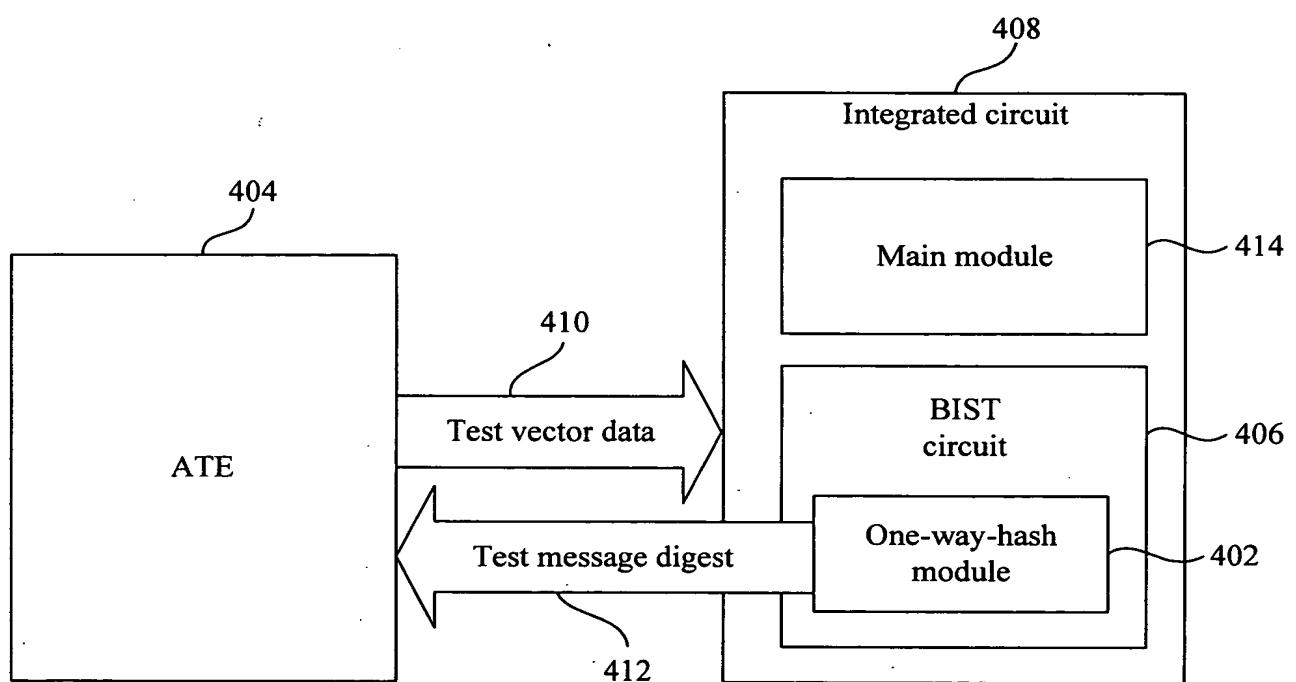


Fig. 4

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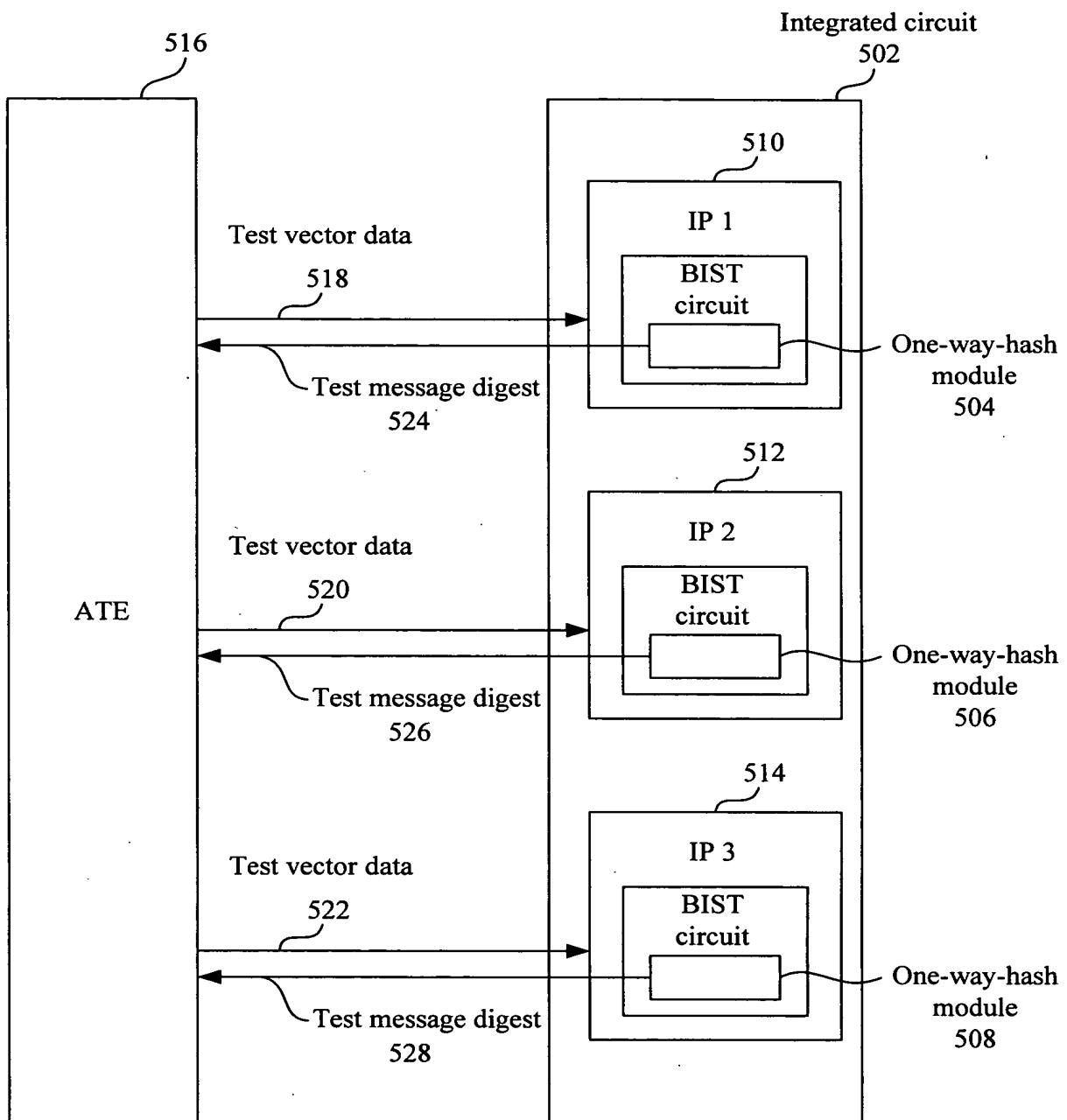


Fig. 5